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**OFFICE OF PETITIONS**

In re Application of	:
Bhushan Mangesh Kanekar et al	: DECISION GRANTING
Application No. 10/723,371	: PETITION
Filed: November 25, 2003	:
Attorney Docket No. CISC110C1	:

This is a decision on petition under 37 CFR 1.181 and 1.10(c), filed May 2, 2005, which is being treated under 37 CFR 1.10(c), requesting that the above-identified application be accorded a filing date of November 25, 2003, rather than the presently accorded filing date of November 26, 2003.

Applicants request the earlier filing date on the basis that the application was purportedly deposited with the U.S. Postal Service (USPS) as Express Mail on November 25, 2003, pursuant to the requirements of 37 CFR 1.10. In support, the petition is accompanied by, *inter alia*, a copy of the Express Mail receipt No. EV332828335US, which is the same Express Mail number found on the original itemized transmittal accompanying the original application papers located in the official file. It is noted that, while the "date-in" on the copy of the Express Mail receipt was left blank, it includes a "USPS" receipt stamp dated "November 25, 2003".

In view of the above, the evidence is convincing that the application was deposited as "Express Mail" with the US Postal Service on November 25, 2003. Accordingly, the instant application is entitled to a filing date of November 25, 2003, and has been so accorded.

The petition is granted. No fee is required and none has been changed.

Telephone inquiries specific to this matter should be directed to Wan Laymon at (571) 272-3220.

This matter is being referred to Publishing Division to be processed into a patent.

  
Frances Hicks

Lead Petitions Examiner  
Office of Petitions  
Office of the Deputy Commissioner  
for Patent Examination Policy